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Temporal Light Artifacts: Test Methods and Guidance for Acceptance Criteria

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CONTENTS

Foreword	iv
1 General	1
1.1 Scope.....	1
1.2 References	1
2 Definitions	3
2.1 Flicker	3
2.2 Flicker Index	3
2.3 Jitter	3
2.4 Maximum Light Output Waveform (MLOW)	4
2.5 Modulation Depth.....	4
2.6 Percent Flicker.....	4
2.7 Phantom Array Effect.....	4
2.8 Short Term Flicker Indicator, P_{st}	4
2.9 Stroboscopic Effect.....	4
2.10 Stroboscopic Visibility Measure (SVM).....	4
2.11 Temporal Light Artifact (TLA)	5
3 Background	5
3.1 TLA in Common Experience.....	5
3.2 Quantification of TLA	5
3.2.1 Modulation Depth and Flicker Index.....	6
3.2.2 Review of IEEE 1789 Metrics and Recommendations	7
3.2.3 Balancing TLA Requirements with Performance Requirements.....	8
3.2.4 Metrics for Objective Assessment of TLA Visibility	9
4 Selected Metrics	14
5 Measurement Method—Light Source	14
5.1 General	14

5.2	Testing Environment.....	15
5.3	Mains Supply	15
5.4	Test Equipment.....	15
5.5	Data Collection	16
5.6	Detailed Instructions	17
5.6.1	Equipment Setup for Light Source DUT.....	18
5.6.2	Test Procedure for Light Source DUT.....	18
5.6.3	Confirm Data Integrity	20
5.6.4	Evaluate Results	21
5.7	Conditions of Testing.....	22
6	Measurement Method—Dimmer.....	23
6.1	General.....	23
6.2	Testing Environment.....	23
6.3	Mains Supply	23
6.4	Test Equipment.....	23
6.5	Data Collection	24
6.6	Detailed Instructions	26
6.6.1	Equipment Setup for Dimmer DUT	26
6.6.2	Test Procedure for Dimmer DUT	27
6.6.3	Confirm Data Integrity	28
6.6.4	Evaluate Results	28
6.7	Conditions of Testing.....	29
7	Recommendations	29
Annex A	31

FIGURES

Figure 1	Definitions of Percent Flicker (Also called Modulation Depth or Modulation Percent) and Flicker Index	3
Figure 2	Example of Stroboscopic Effect.....	6
Figure 3	Comparison of IEEE 1789 Recommended Limits with Several Existing Light Sources and with SVM and Pst	7
Figure 4	Plot of ASSIST and IEC Pst metrics Calculated for a 30% Modulation Depth Single-Frequency Sine Wave Light Waveform.....	10
Figure 5	Plot of the Visibility Threshold	11
Figure 6	Plot of the SVM Metric, as a Function of Frequency, for Single Sine Wave Modulation	12
Figure 7	Plot of the SVM Metric.....	13
Figure 8	Equipment setup for TLA measurement of a light source.....	14
Figure 9	General Test Procedure for Light Sources.....	18
Figure 10	Setup Measurement Equipment and Light Source DUT	18
Figure 11	Procedure for Collecting Light Source TLA Data	20
Figure 12	Confirm Light Source Data Integrity	21
Figure 13	Procedure to Evaluate Light Source DUT Measurements	22
Figure 14	Equipment Setup for Dimmer Measurement	23
Figure 15	Output of Dimmer DUT.....	25
Figure 16	General Test Procedure for Dimmers	26
Figure 17	Setup Measurement Equipment and Dimmer DUT.....	26
Figure 18	Procedure to Collect Dimmer Data.....	27
Figure 19	Procedure to Confirm Dimmer Data Integrity	28
Figure 20	Procedure to Evaluate Dimmer DUT Measurements	29

TABLES

Table 1	Equipment Requirements for TLA Measurement.....	16
Table 2	Data Sampling Scheme.....	17
Table 3	Column Headings for Measurement Data Map	17
Table 4	Equipment Requirements for Dimmer TLA Measurement	24
Table 5	Format for Data Results Table	25
Table 6	Guidelines for Pst and SVM Acceptance Criteria.....	30

Foreword

A NEMA working group formed by a compilation of the Lighting, Lighting Controls, and Luminaire Sections has prepared this standard, *Temporal Light Artifacts: Test Methods and Guidance for Acceptance Criteria*. This standard provides measurement methods for metrics that address temporal light artifacts (TLA) for light sources, as well as measurement methods for leading-edge phase cut dimmers. It provides initial broad guidelines for limits on these metrics.

Inquiries, comments, and proposed or recommended revisions should be submitted to:

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Section approval of the standard does not necessarily imply that all section members voted for its approval or participated in its development.

At the time the standard was approved, the Lighting Controls, Light Source and Luminaire sections were composed of the following members:

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Appleton Group
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1 General

1.1 Scope

The purpose of the standard is to recommend a method of quantifying the visibility of temporal light artifacts (TLA) and to recommend initial, broad application-dependent limits on TLA.

The photometric recommendations and measurement methods are applicable to any lighting equipment (e.g., luminaires, light engines, self-ballasted lamps, drivers, and sensors) with any control system. Specific recommendations and measurement methods for controls are only included for phase-cut dimming.

The standard applies to visibility of TLA to human observers in applications with limited speeds of motion, such as an office environment. It does not address interference with optical equipment such as cameras and bar-code scanners. It does not address the potential for adverse stroboscopic effect in high-speed environments, such as machine shops. It does not address the phantom array effect.